



Patent

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): James H. Schaffner, et al.)	Re: Information Disclosure Statement
Serial No.: 10/786,736)	Group: 2817
Filed: February 24, 2004)	Examiner: Kimberly Glenn
)	Our Ref: B-4958NP 621373-2
For: "RF MEMS SWITCH WITH INTEGRATED IMPEDANCE MATCHING STRUCTURE")	Date: October 17, 2005

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The filing of this Information Disclosure Statement shall not be construed as an admission against interest in any manner. (Notice of January 9, 1992, 1135 O.G. 13-25, at 25.)

The person making this statement is the practitioner who signs below on the basis of information supplied by an individual associated with the filing and prosecution of this application (37 C.F.R. § 1.56(c)) and on the basis of information in the practitioner's file.

I hereby certify that this correspondence is being deposited with the United States Postal Service with sufficient postage as first-class mail in an envelope addressed to the "Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450", on October 17, 2005 by Guillermo Gonzalez.

Respectfully submitted,



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Enclosures: Form PTO-1449 (modified) (2 pages)
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LIST OF PATENTS AND PUBLICATIONS STATEMENT	APPLICANTS James H. Schaffner, et al.	
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U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	ISSUE DATE	NAME	CLASS	SUB- CLASS	FILING DATE or 102(e) DATE IF APPROPRIATE
	2003/0222738	12/2003	Brown, et al.	333	206	
	2004/0113713	6/2004	Zipper, et al.	333	206	
	5,208,603	5/1993	Yee	343	909	
	5,278,562	1/1994	Martin, et al.	342	1	
	5,619,365	4/1997	Rhoads, et al.	359	245	
	5,619,366	4/1997	Rhoads, et al.	359	248	
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	6,469,673	10/2002	Kaiponen	343	703	
	6,897,810	5/2005	Dai, et al.	343	700 MS	

	<u>DATE CONSIDERED</u>

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

	Bushbeck, M.D., et al., "a Tunable Switcher Dielectric Grating," <i>IEEE Microwave and Guided Wave Letters</i> , Vol. 3, No. 9, pp. 296-298 (September 1993)
	Chambers, B., et al., "Tunable Radar Absorbers Using Frequency Selective Surfaces," <i>11th International Conference on Antennas and Propagation</i> , Vol. 50, pp. 832-835 (2002)
	Chang, T.K., et al., "Frequency Selective Surfaces on Biased Ferrite Substrates," <i>Electronics Letters</i> , Vol. 30, No. 15, pp.1193-1194 (July 21,1994)
	Gianvittorio, J.P., et al., "Reconfigurable MEMS-enabled Frequency Selective Surfaces," <i>Electronic Letters</i> , Vol. 38, No. 25, pp. 1627-1628 (December 5, 2002)
	Lima, A.C., et al., "Tunable Frequency Selective Surfaces Using Liquid Substrates," <i>Electronic Letters</i> , Vol. 30, No. 4, pp. 281-282 (February 17, 1994)
	Oak, A.C., et al. "A Varactor Tuned 16 Element MESFET Grid Oscillator," <i>Antennas and Propagation Society International Symposium</i> . pp. 1296-1299 (1995)

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